

Summary _____

- Proven track record with a history of innovation.
- Experience designing complex systems with resource constraints.
- A wide range of machine learning experience.

Education

East Tennessee State University

Johnson City, TN, USA

Aug 2014 - Dec 2017

B.S. IN MATHEMATICS (STATISTICS CONCENTRATION)

- Undergraduate Research: Test for Randomness based on the Arcsine Distribution
- Advisor: Prof. Anant Godbole
- Cumulative GPA: 3.7 / 4.0
- Magna Cum Laude

Languages_____

English: FluentMandarin: Native

Experience

Johnson City and Columbia, TN

Nail Technician 2013-2019

- Recieved Nail Technician License
- Held a full tiem job during my education at ETSU (35-45 hours per week).
- Learned to communciate effectively with customers in order to determine customer requirements.
- · Developed an understanding of American culture, language, and diversity; learned to fit into a new environment.

Programming Languages and Skills

Programming Languages Python, R, C, C++, Java, Cuda

Machine Learning Neural Networks, Agent Based Modeling, Deep Learning, Decision Trees, SVMs, Reinforcement Learning

Dev-ops Docker, AWS, Jenkins

Honors & Awards

ADTRAN

December, 3rd Place, Best Innovation, One-Class Support Vector Machine (SVM) with a multi-class classifier for

2017 labeling and troubleshooting build failures

May, 2017 1st Place, Best Innovation, Classifying encrypted payloads using deep neural networks.

December, 1st Place, Best Innovation, A Convolutional Neural Network for feature detection in packet processing

2016 systems.

July, 2015 1st Place, Best Innovation, Flow Utility Prediction Using Recurrent Neural Networks

Publications

- 1. M. Arnold. Predictive networking and optimization for flow-based networks. Master's thesis, University of Alabama in Hunstville, 2017. URL https://arxiv.org/pdf/1707.06729.pdf
- 2. M. Arnold, D. Shenviwagle, and L. Yilmaz. Scibrowser: A computational ethnography tool to explore open source science communities. In *Proceedings of the 48th Annual Southeast Regional Conference*, ACM SE '10, pages 26:1–26:6, New York, NY, USA, 2010. ACM. ISBN 978-1-4503-0064-3. doi: 10.1145/1900008.1900045. URL http://doi.acm.org/10.1145/1900008.1900045